

产品名称 Description		

	产品料号 Part No.	产品型号规格 Description
包括但不限于右边所列产品	3720MXXX022XXXXXX	0.5BTB-NPin 公座H2.2
	3720MXXX012XXXXXX	P型0.5BTB-NPin 公座H1.23
	3720MXXX037XXXXXX	0.5BTB-NPin 公座H3.7
	3723-MXXX008XXXXXX	0.5BTB-NPin 双槽型 公座H3.7
	3723-MXXX010XXXXXX	0.5BTB-NPin 双槽型 公座H1.0
	3723-MXXX013XXXXXX	0.5BTB-NPin 双槽型 公座H1.3
	3723-MXXX020XXXXXX	0.5BTB-NPin 双槽型 公座H2.0
	3720FXXX013XXXXXX	0.5BTB-NPin 母座H1.32
	3720FXXX023XXXXXX	0.5BTB-NPin 母座H2.3
	3720FXXX043XXXXXX	0.5BTB-NPin 母座H4.3
	3720FXXX018XXXXXX	P型0.5BTB-NPin 母座H1.85
	3723-FXXX022XXXXXX	0.5BTB-NPin 双槽型 母座H2.2
	3723-FXXX030XXXXXX	0.5BTB-NPin 双槽型 母座H3.0
	3723-FXXX035XXXXXX	0.5BTB-NPin 双槽型 母座H3.5
	3723-FXXX040XXXXXX	0.5BTB-NPin 双槽型 母座H4.0
	3723-FXXX045XXXXXX	0.5BTB-NPin 双槽型 母座H4.5

1. SCOPE ()

This product specification defines the product performance and the test methods to ascertain the performance of the (0.5mm Board To Board) Connector ,which si designed and manufactured by JILN Electronic Co.,Ltd.This product specification is applicable but not only for those part numbers which be shown in the cover page.

本产品规格书规定了由锦凌电子有限公司设计生产的(0.5mm板对板)型连接器,产品的特性及产品的测试方法。本产品规格书适用于但不局限于封面所显示的产品料号

2. REFERENCE DOCUMENTS

MIL-STD-1344	Test method for electrical connector 电子连接器方法
MIL-STD-202	Test method for electrical connectors 电子零件测试方法
EIA364	Test method for electrical connectors 电子零件测试方法
JIS C 0051	Test method for electrical connectors 电子零件测试方法
MIL-G-45204C	Specification for gold plating 镀金规格
IEC-512-3	IEC standard for current carrying capacity tests IEC 电流测试标准
QQ-N-290A	Specification for nickel plating 镀镍规格
MIL-P-81728A	Specification for tin/lead plating 镀锡规格
MIL-T-10727B	Specification for tin plating 镀锡规格
UL498	UL standard for safety of attachment plug and receptacle UL安规要求标准
IEC62321	Determination of total lead &cadmium content 总铅和总镉含量测定
IEC62321	Determination of total lead &cadmium content 总铅和总镉含量测定
IEC62321	Determination of heavy metals content 重金属含量测定
IEC62321	Determination of total lead &cadmium content 总铅和总镉含量测定

3. FEATURE & DIMENSIONS

3.1. PRODUCT DIMENSION (产品尺寸)

These connectors shall have the dimensions as shown in drawing.

本产品的相关尺寸参见图面.

3.2. PCB/panel layout (! 电" 板# 局)

The recommended PCB layout is shown in drawing.

本产品适用的 PCB layout 参见图面.

3. Cool Down (mn)

Cool down shall not exceed 6°C per second.

(mn a E 不bc 6°C/d.)

4.3. RESISTANCE TO SOLDER HEAT (o L 接)

WAVE SOLDER (p q L 接)

Each cycle consists of three consecutive phases.

(T U L 接VW包括X U连Y Z [.)

1.Preheat (\])

The steady temperature of the preheat zone is 90G125F .

\] r j s DE * + e 90G125F .

2. Soldering (L 接)

To avoid the secondary tin-melting, the temperature on PCB upper surface is 160°C Max. for products with lead, or 200°C Max. for lead-free products. The temperature of the PCB bottom surface shall not be exceed 100°C more than the temperature of the PCB upper surface. The peak temperature is during 230~250°C for products with lead, or 255~265°C for lead-free products. The tin dip time is duration for 3~5 seconds.

(有铅产品板面DE 不Mbc 160F , t 铅产品板面DE 不的bc 200F , f u v w x 零件y z { 锡。板面DE 7板| 的DE D} 不Mbc 100F。板3DE q ~有铅产品 e 230G250F , t 铅产品* + e 260G270F。锡hi * + e 3G10d.)

3.Cool Down (mn)

Cool down shall not exceed 6F per second.

(mn a E 不bc T d 6F)

Note:

Device temperature measurements are referenced from the top-center of the package outer surface.

(设 DE 量测hf i 测量 准.)

PERFORMANCE AND TEST DESCRIPTION ()

REQUIREMENT (要求)

Product is designed to meet electrical,mechanical,and environmental performance requirements specified in Table 1

(本产品设计, - 4 5 6所列的1 2 , 电器及 要求)

TEST CONDITION (测试 件)

Unless otherwise specified,all tests shall be performed at ambient environmental conditions.

(特 , 所有测试的 D 件3)

SAMPLE SELECTION (品)

Test samples shall be selected at random from current production. No test samples shall be reused.

Samples are pre-conditioned with 10cycles of durability. Each group shall be containing 5 test samples.

(测试品 生产的产品 1 , 所有测试c 的 品不M重 O用。 品f \ 10z , T 测试 有5U 品.)

5.4. TEST SEQUENCE (测试)

Product qualification test sequence as shown in Table II.

(产品品 测试 见45y)

Table I: Test Requirements and Test Methods

4 5 6 : 测试要求和测试方法

Items ()	Requirements (要求)	Test Methods (测试方法)
1. Confirmation of Product (产品)	Product shall be conforming to the requirements of applicable product drawing 产品 , - 相关产品图面的要求	Visually dimensions and functionally inspected per applicable product drawing. : ; 产品相关图面 , 产品的Q 尺寸及
2. Contact Resistance (接I)	30 m Max.Inital j 30 m	Subject mated contacts assembled in housing to closed circuit of 100 mA max.20 mV max. 所 定e Q 的J 子连接 6U封 S" 测试 : 电流100mA max,电A 20 mV max. 适用 : MIL-STD-202 , 方法 307。
3. Insulation Resistance ()	500 M Min j 500 M	Measure by applying test potential between the adjacent contacts,and between the contacts and ground in the mated connector . MIL-STD-202, Method 302, Condition B (500 V DC 10%). 测试产品相 J 子i f 及J 子7接 i 的电 适用 : MIL-STD-202,方法 302 , 件 B (500V DC 10%)
4. Dielectric Withstanding Strength (O电A)	Connector must withstand test potential os ,annec	

<p>5. Durability (Repeated Mating/Un-mating) 可靠性</p>	<p>Contact Resistance: 50 mΩ Max. after testing. 测试 接触电阻 ≤ 50mΩ</p>	<p>Repeat mate and unmated for connector 500 cycles, At a speed of 300 mm/minute 重 复 行 为 - 产品 500 次 , 速 度 300mm/ 分 的 a E 测试。</p>
<p>6. Connector Pin Mating/Un-mating Force /</p>	<p>Mating force: (60)gf/Pin Max. Un-mating force: (10)gf/Pin Min. j (60) gf/Pin j (10) gf/Pin</p>	<p>At a speed of 25 ± 3 mm/minute, apply axial insert the mating part into fully or pull out from the subject product. 以 25 ± 3mm/ 分 的 a E , 对 件 测 产 品 测 产 品 .</p>
<p>7. Contact Retention Force (J 子)</p>	<p>(0.20)kgf/Pin Min. j (0.20)kgf/Pin</p>	<p>Apply axial pull out force at a 25 ± 3mm/minute On the contact assembled in the housing. 以 25 ± 3mm/ 分 的 a E 本 g J 子.</p>
<p>8. Thermal shock (I)</p>	<p>After testing, no damage, Contact Resistance ≤ 35 mΩ max.. Dielectric Strength should be OK, Insulation Resistance should be 500 MΩ min. (测试 , 产 品 t , 接 触 : 35 mΩ j 电 A 测试 OK, 500MΩ j ;)</p>	<p>is no more than 30 seconds. Total 5 cycles. MIL-STD-202, Method 107D, condition A. (DE : -55°C ~ +85°C -55°C , 30 min ± +85°C 30 min ± hi 不 bc 30 d 10U . 用 : MIL-STD-202 , 方 法 107 , 件 A.)</p>
<p>9. Humidity (D)</p>	<p>After testing, no damage, Contact Resistance ≤ 35mΩ max.. Dielectric Strength should be OK, Insulation Resistance should be 500MΩ min. 测试 , 产 品 t , 接 触 : 35 mΩ j 电 A 测试 OK, 500MΩ j ;</p>	<p>Temperature: 40 ± 2°C. Relative Humidity: 90-95%. Duration: 96 Hours. MIL-STD-202, Method 103, condition B. DE : 40 ± 2°C. 相对 湿 度 : 90-95%. Y hi : 96 . 适用 : MIL-STD-202 , 方 法 103 , 件 B.</p>
<p>10. Solder ability (9L 性)</p>	<p>giving a magnification of 10 X for any damage such as pinholes, void or rough surface. 品 e 测试 , e 10 的 显 示 , Q : , L , Q E)</p>	<p>Soldering time: 4 to 6 seconds. Temperature: 260 ± 5°C. MIL-STD-202, Method 208. L 接 触 : 4~6 d. DE : 260 ± 5°C. L 锡 面 : 95% f g 适用 : MIL-STD-202 , 方 法 208.</p>

<p>11. Humidity (D)</p>	<p>After testing, no damage, Contact Resistance 35m max.. Dielectric Strength should be OK, Insulation Resistance should be 500M min.</p> <p>测试 , 产品 t , 接 I : 35 m j o电A测试 OK, 500M j ;</p>	<p>Temperature: 40 2^C. Relative Humidity: 90-95%. Duration: 96 Hours.</p> <p>MIL-STD-202, Method 103, condition B.</p> <p>DE : 40 2^C.</p> <p>相对 E : 90-95%.</p> <p>Yhi : 96 .</p> <p>适用 : MIL-STD-202 , 方法 103 , 件 B.</p>
<p>12. Solder ability (9L 性)</p>	<p>giving a magnification of 10 X for any damage such as pinholes, void or rough surface.</p> <p>品 e 测试 , e 10 的显 3 , Q : , L , Q E)</p>	<p>Soldering time: 4 to 6 seconds.</p> <p>Temperature: 260 5^C.</p> <p>MIL-STD-202, Method 208.</p> <p>L 接 hi : 4~6 d.</p> <p>DE : 260 5^C.</p> <p>L 锡面 : 95% f g</p> <p>适用 : MIL-STD-202 , 方法 208.</p>

Table II: Product Qualification Test Sequence

45y : 产品测试

Test Description 测试	TestGroup 测试						
	A	B	C	D	E	F	G
1. Conformation of Product 产品	1,7	1,4	1,9	1,9	1,3	1,9	1,9
2. Contact Resistance 接I	2,6		2,6	2,6		2,6	2,6
3. Insulation Resistance	3		3,7	3,7		3,7	3,7
4. Dielectric Withstanding Voltage o电A	4		4,8	4,8		4,8	4,8
5. Durability (Repeated Mating/Un-mating) o 性	5						
6. Connector Pin Mating/Un-mating Force & J子 / "		2					
7. Contact Retention Force J子 "		3					
8. Thermal Shock]			5				
9. Humidity (Steady State) D				5			
10. Solder-ability oL 性					2		
11. Salt Spray						5	
12. High Temperature Life I D#							5

Table III: Reflow Soldering Profile

附表三：回流焊接曲线图

Lead-free reflow profile requirements:

无铅回流焊接要求：

Parameter 参	Reference 参	Specification 规格
K Dr Ramp-up	25°C ~ 150°C	3°C /S Max
\] r (Pre-heating) Temperature Min(Tsmin) Temperature Max(Tsmax) Time(Tsmin to tsmax)	150F ~ 200F	60~180sec
Time maintained above(h i) Temperature(TL) Time(tL)	217°C	60~150sec
Time within 5°C of actual peak Temperature(tp)	260-/+5°C	20~40sec
mnr Cooling	Ramp-Down Rate	6°C /S(Max)
Time 25°C to Peak Temperature	25°C ~ Peak Temp.	8 minutes maximum

This profile is the minimum requirement for evaluating soldering heat resistance of components. Heat transfer method used for reflow soldering is hot air convection. The actual air temperatures used to achieve the specified profile largely dependent on the reflow equipment.

U R图 件器件L接]的 本要求。 用e对L接 的] 方>] 对流。 特
定 R图 DE 要: 7S流L接设 。

5.

5.1 (料的包8对(料有6定的 用和 封 用, (料e c 不 。

5.2 包8 u ,u uA和u 要求。

5.3 j 包8& 的标 有 标 产品型号 名称 (料 和 量。

5.4 包8 的产品, e DE -10FG+40F, 相对 Ee 80%f 3, VH t 性,
性 性 的 B, eg 件3, 生产 W BW, e
(料 - 格品。